

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Won-Jun LEE, et al.

Serial No.: 10/763,356 Examiner: Anita Karen Alanko

Filed: January 23, 2004 Group Art Unit: 1765

Confirmation No.: 7097

For: ETCHING METHOD FOR MANUFACTURING SEMICONDUCTOR
DEVICE

Date: January 3, 2007

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Alexandria, VA 22313-1450

**APPLICANT'S COMMENTS ON EXAMINER'S STATEMENT OF REASONS FOR
ALLOWANCE**

In the Examiner's Statement of Reasons for Allowance, the Examiner recited portions of the allowed independent claims and stated that prior art could not be located that taught the recited portions. The applications note that it is a well-known tenet of patent law that each allowed patent claim stands alone. Further, although the Examiner has indicated at least one reason for allowance, there can be other reasons that claims are allowable.

Customer No. 20575

Respectfully submitted,
MARGER JOHNSON & McCOLLOM, P.C.



Hosoon Lee, Reg. No. 56,737

MARGER JOHNSON & McCOLLOM, P.C.
210 SW Morrison Street, Suite 400
Portland, OR 97204
503-222-3613